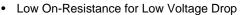


P-Channel 30 V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	$R_{DS(on)}(\Omega)$ Max.	I _D (A)	Q _g (Typ.)	
- 30	$0.0068 \text{ at V}_{GS} = -10 \text{ V}$	- 68 ^d	90 nC	
	0.0095 at V _{GS} = - 4.5 V	- 58 ^d	90 110	

FEATURES



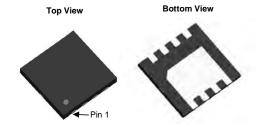


100 % R_g and UIS Tested

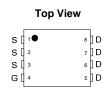
RoHS COMPLIANT

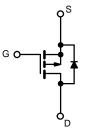
APPLICATIONS

- Battery, Load and Adaptor Switches
 - Notebook Computers
 - Notebook Battery Packs



DFN 3x3 EP





P-Channel MOSFET

Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	V _{DS}	- 30	V	
Gate-Source Voltage	V _{GS}	± 20		
	T _C = 25 °C		- 68 ^d	
Continuous Drain Current (T _{.1} = 150 °C)	$T_C = 70 ^{\circ}C$	I _D	- 58 ^d	
Continuous Brain Carrotti (1) = 100 °C)	$T_A = 25 ^{\circ}C$	U. O	- 34 ^{a, b}	
	T _A = 70 °C		- 21 ^{a, b}	A
Pulsed Drain Current (t = 100 μs)	I _{DM}	- 272	A	
Continuous Source-Drain Diode Current	T _C = 25 °C	I-	- 68 ^d	
Continuous Source-Dialit Diode Current	T _A = 25 °C	- Is -	- 5.9 ^{a, b}	
Avalanche Current		I _{AS}	- 26	
ngle-Pulse Avalanche Energy L = 0.1 mH		E _{AS}	93	mJ
	T _C = 25 °C		81	
Maximum Bawar Dissipation	T _C = 70 °C	D ₋	51.84	w
Maximum Power Dissipation	T _A = 25 °C	P _D	5.4 ^{a, b}	VV
	T _A = 70 °C		3.5 ^{a, b}	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	
Soldering Recommendations (Peak Temperature) ^{e, f}		260	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^{a, c}	t ≤ 10 s	R _{thJA}	16	24	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	1.8	2.5]	

Notes:

- a. Surface mounted on 1" x 1" FR4 board.
- b. t = 10 s.
- c. Maximum under steady state conditions is 70 °C/W.
- d. Package limited.
- e. The DFN3X3 is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- f. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.



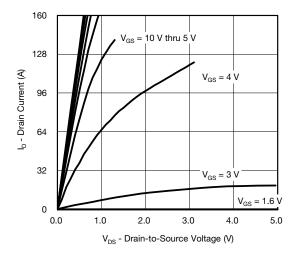


Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0$, $I_D = -250 \mu A$	- 30			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	1 2504		- 22		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = - 250 μA		4.1			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	- 1.2		- 2.5	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 10 \text{ V}$			± 100	nA	
	I _{DSS}	V _{DS} = - 24 V, V _{GS} = 0 V			- 1	μА	
Zero Gate Voltage Drain Current		V _{DS} = - 24 V, V _{GS} = 0 V, T _J = 55 °C			- 5		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge -10 \text{ V}, V_{GS} = -10 \text{ V}$	- 30			Α	
	R _{DS(on)}	V _{GS} = - 10 V, I _D = - 15 A		0.0068	0.0085	Ω	
Drain-Source On-State Resistance ^a		V _{GS} = - 4.5 V, I _D = - 10 A		0.0095	0.013		
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 10 V, I _D = - 15 A		60	0.010	S	
Dynamic ^b	-	-					
Input Capacitance	C _{iss}			6345			
Output Capacitance	C _{oss}	V _{DS} = - 15 V, V _{GS} = 0 V, f = 1 MHz		1303		pF	
Reverse Transfer Capacitance	C _{rss}			520			
Treverse transfer Supusitance		V _{DS} = - 15 V, V _{GS} = - 10 V, I _D = - 10 A		91	407	nC	
Total Gate Charge	Q _g	B3 - 7 G3 - 7 B		42	137 66		
Gate-Source Charge		V _{DS} = - 15 V, V _{GS} = - 4.5 V, I _D = - 10 A		14	00		
Gate-Drain Charge	Q _{gd}			29			
Gate Resistance	R _g	f = 1 MHz	0.5	2.5	4.9	Ω	
Turn-On Delay Time	t _{d(on)}		0.0	18	7.0		
Rise Time	t _r	$V_{DD} = -15 \text{ V, R}_{1} = 1.5 \Omega$		15		-	
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -10 \text{ A}, V_{GEN} = -10 \text{ V}, R_a = 1 \Omega$		59			
Fall Time	t _f			11			
Turn-On Delay Time	t _{d(on)}			65		ns	
Rise Time	t _r	$V_{DD} = -15 \text{ V, R}_1 = 1.5 \Omega$		64			
Turn-Off DelayTime	t _{d(off)}	$I_D \cong -10 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_q = 1 \Omega$		47		1	
Fall Time	t _f	SEN 9		25		1	
Drain-Source Body Diode Characteris				20			
Continous Source-Drain Diode Current I _S		T _C = 25 °C			- 68		
Pulse Diode Forward Current (100 μs)	I _{SM}	C == -			- 272	A	
Body Diode Voltage	V _{SD}	I _S = -3 A, V _{GS} = 0		- 0.75	- 1.20	V	
Body Diode Reverse Recovery Time t _{rr}				29	46	ns	
Body Diode Reverse Recovery Charge		I _F = - 10 A, dl/dt = 100 A/μs, T _{.I} = 25 °C		15	28	nC	
Reverse Recovery Fall Time	t _a			9		ne	
Reverse Recovery Rise Time	t _b	1		14		ns	

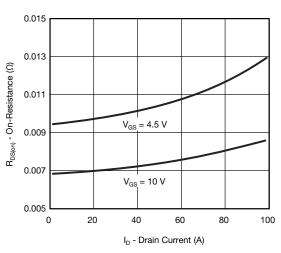
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

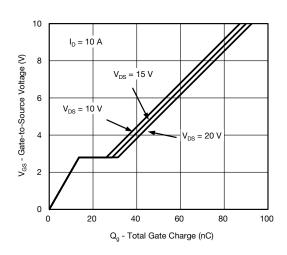




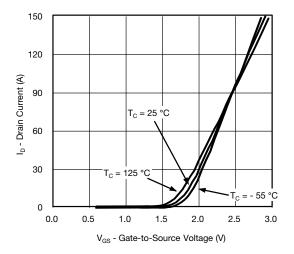
Output Characteristics



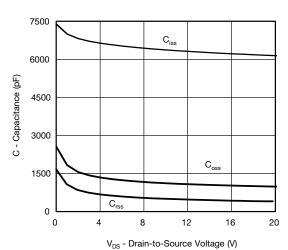
On-Resistance vs. Drain Current



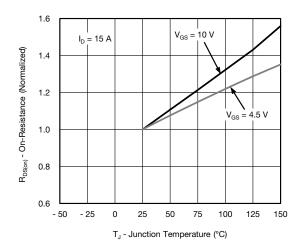
Gate Charge



Transfer Characteristics

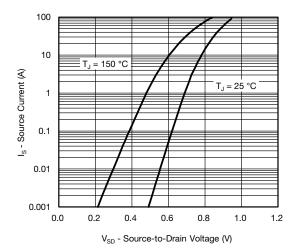


Capacitance

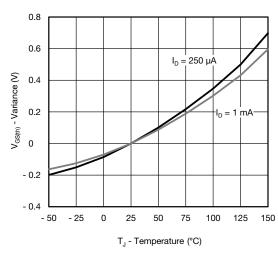


On-Resistance vs. Junction Temperature

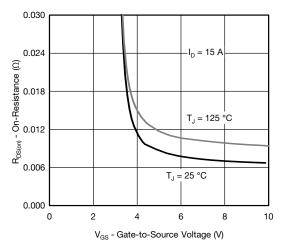




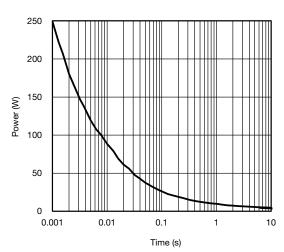
Source-Drain Diode Forward Voltage



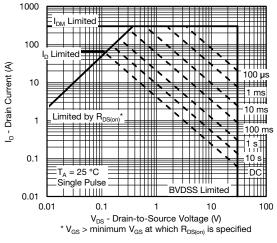
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage

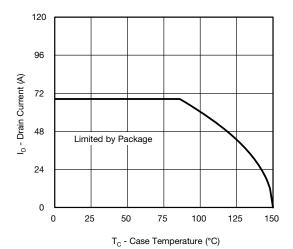


Single Pulse Power, Junction-to-Ambient

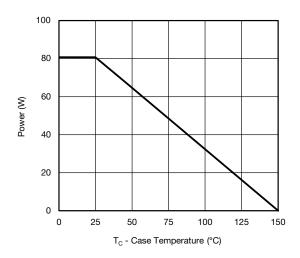


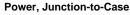
Safe Operating Area

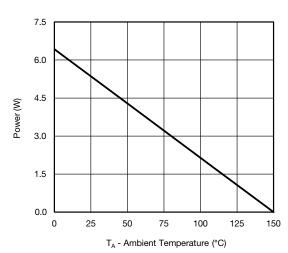




Current Derating*



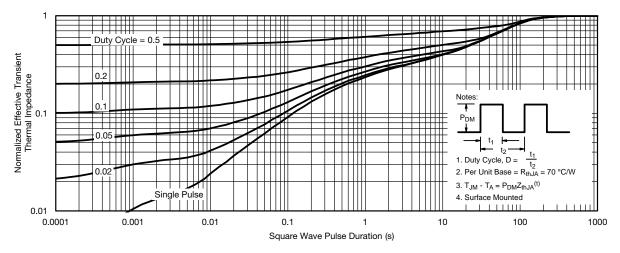




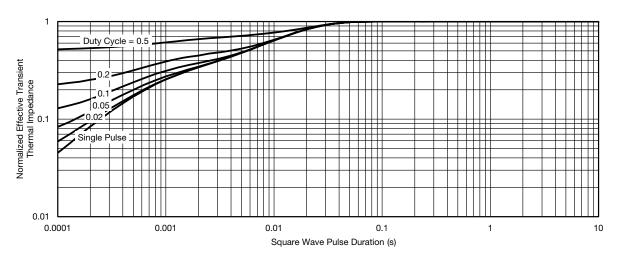
Power Derating, Junction-to-Ambient

 $^{^*}$ The power dissipation P_D is based on $T_{J(max.)}$ = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case





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